

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination	
	10/777,884	ZEHNLE ET AL.	
Examiner	Art Unit	2618	Page 1 of 1
Lana N. Le			

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,847,802	01-2005	Migliaccio, Riccardo	455/186.1
*	B	US-2002/0120943	08-2002	Seto et al.	725/135
*	C	US-6,141,536	10-2000	Cvetkovic et al.	455/45
*	D	US-2005/0020223	01-2005	Ellis et al.	455/186.1
*	E	US-5,797,087	08-1998	Lee, Hyo Chan	455/181.1
*	F	US-5,393,713	02-1995	Schwob, Pierre R.	455/186.1
*	G	US-5,819,166	10-1998	Kimura et al.	455/186.1
*	H	US-2005/0166257	07-2005	Feinleib et al.	725/135
*	I	US-6,411,800	06-2002	Emerson, III, Harry E.	455/186.1
*	J	US-6,615,043	09-2003	van de Berg, Petrus	455/185.1
*	K	US-4,737,993	04-1988	DeVilbiss, Warren C.	455/180.1
*	L	US-5,471,662	11-1995	Shiota, Shinichi	455/184.1
*	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.